



IECQ QUALITY ASSESSMENT SYSTEM (IECQ)

For rules and details of the IECQ visit www.iecq.org

IECQ Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.:	IECQ-L ULTW 16.0003-15	Issue No.:	1	Status:	Current
Additional Site to Certification:		IECQ-L ULTW 16.0003		Originally Issued: 2016/07/28	
Supersedes:		Issue Date:	2024/08/07	Site Added:	2024/08/07
CB Reference No.:	50600328 ITL	Expiration:	2025/07/27		

Materials Analysis Technology (Shanghai) Ltd.

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The organization, facilities and procedures have been assessed by the IECQ Certification Body in accordance with IECQ 03-1 and IECQ 03-6 for issuance of this certificate and found to be in conformity with the applicable requirements of the IECQ Independent Testing Laboratory Assessment Program Requirements Scheme and in respect of ISO/IEC 17025:2017 for the testing of component product under the IECQ.

Scope:

The reliability testing of semiconductors in component level, board level, system level.
See attached Schedule.

-- Attached Schedule: IECQ-L_ULTW_50600328 ITL. 08-07-24.pdf --

Approved by Certification Body (CB): DQS Group - DQS Taiwan Inc.

8F, 23, Yuan Huan West Road,
Feng Yuan Dist., Taichung City
Taiwan

Authorized person:
Bob CHEN



The validity of this certificate is maintained through on-going surveillance audits by the IECQ CB issuing this certificate.

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Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 16.0003-15

CB Certificate No.: 50600328 ITL

Schedule Number: IECQ-L ULTW 16.0003-15-S Rev No.: 1 Revision Date: 2024/08/07 Page 1 of 1

Appendix-1 (50600328 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
Optical Microscope (OM)	T-OMI-3
High Temperature Operation Life test (HTOL)	IEC 60068-2-1, JESD22-A108
Low Temperature Operation Life test (LTOL)	IEC 60068-2-1, JESD22-A108
Bias Life test (BLT)	JESD22-A108
Highly Accelerated Stress test (HAST)	JESD22-A110
Temperature and Humidity with Bias test (THB)	JESD22-A101

Technical Reviewer of DQS: Paul Yang Date: 8/7/2024

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